



Supplementary Figure S1. 3x3- μm tapping-mode AFM images of hole-doped mTFF-C n SISC $_2$ F $_5$ films spin-cast on quartz substrate. Solution-doped films: **(a)** $n = 2$ ($R_{\text{rms}} = 9.6 \text{ \AA}$), **(b)** 3 (11.2 \AA), **(c)** 4 (6.3 \AA); and solid-state-doped films: **(d)** 2 (11.1 \AA), **(e)** $n = 6$ (10.6 \AA). Tool: JPK Nanowizard®ULTRA Speed AFM. R_{rms} is root-mean-square roughness.